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Radiation Tolerant Electronics, Volume II

Guest Editor:

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Deadline for manuscript submissions:

closed (30 June 2022)

Message from the Guest Editor

The main aim of this Special Issue is to seek high-quality submissions that highlight emerging applications, address recent breakthroughs in modeling radiation effects in advanced electronic devices and circuits, the design of radiation hardened analog, mixed-signal, RF and digital integrated circuits and radiation hardness testing methodologies. The topics of interest include, but are not limited to:

- Basic mechanisms of radiation effects in electronic devices
- Compact modeling of radiation effects and circuit/layout level optimization (TID and SEE)
- Radiation effects in power devices/circuits
- Design of radiation hardened integrated circuits (analog/RF/mixed-signal/digital)
- Radiation hardening and fault tolerance in FPGAs
- Radiation hardness assurance testing

Welcome to contribute!











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Editor-in-Chief

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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